



Channel Simulation Over DDR4/5 and Above

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Two Concerns:


- As the transmission rate of memory bus goes beyond 5Gbps, besides the well-known timing and overshoot/undershoot analysis, it requires BER prediction analysis and channel analysis
- Two additional concerns we need to face while using channel engine to deal with memory bus:

- Asymmetric rising/falling edges

Different from differential serial buses, single-ended memory buses will have non-symmetrical rising and falling edges due to the inherent difference between these two kinds of circuits

- Strobes as timing reference

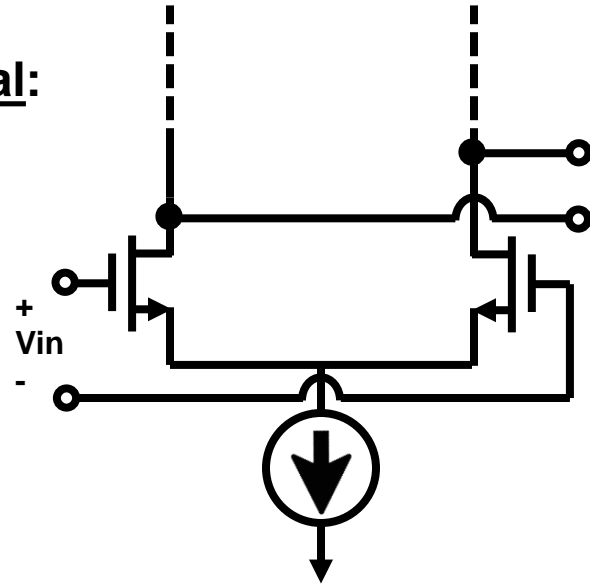
While the sampling clock ticks in serial bus are recovered from the signal itself by CDR, the sampling clocks or the timing references in memory bus will be the strobes rather than any recoveries



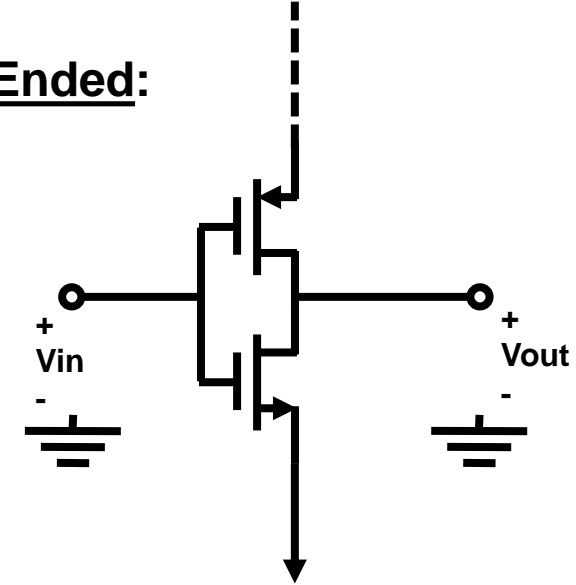
Asymmetric Rising and Falling Edges

Circuits

Differential:

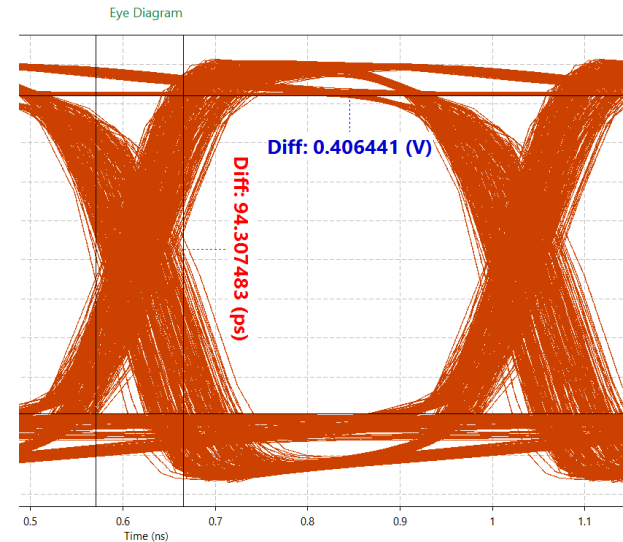
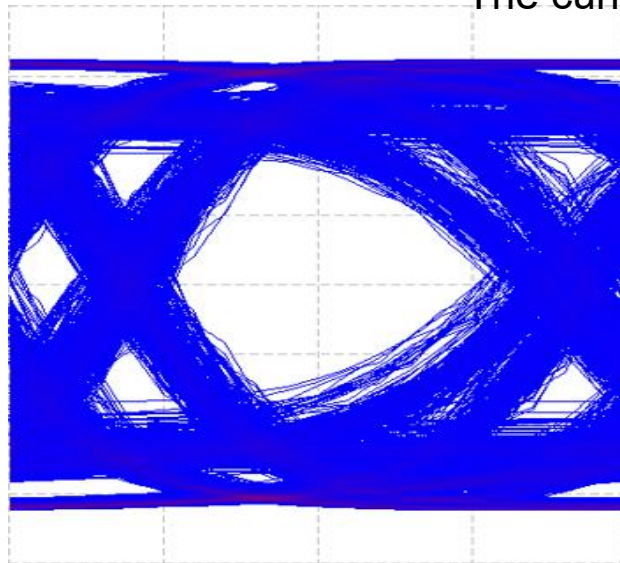


Single-Ended:



The current path during a binary "1" bit

The current path during a binary "0" bit

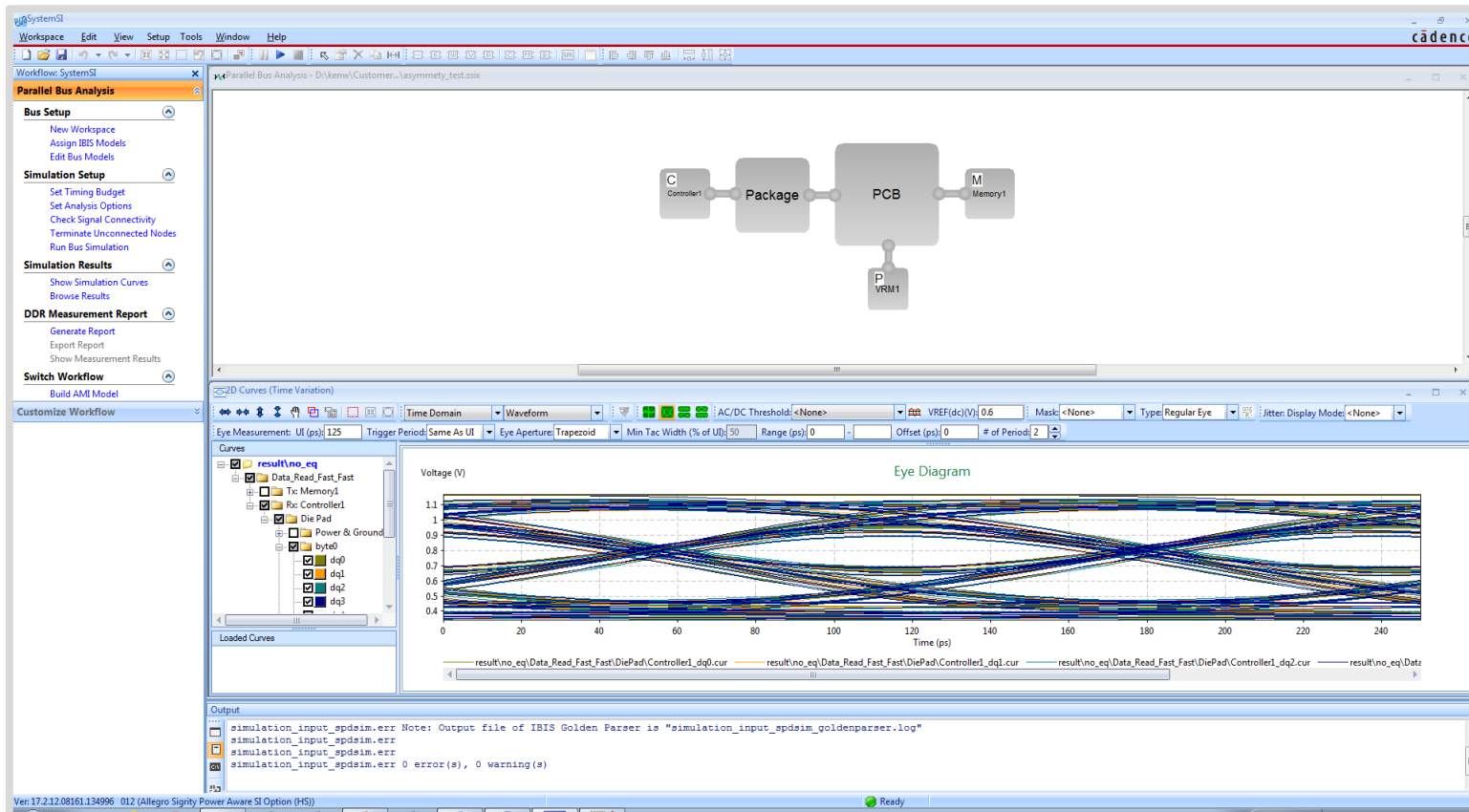


Overview

- As channel simulation and IBIS-AMI modeling methods are adapted from serial link to DDR interface analysis, we encounter IBIS I/O models with asymmetric rising and falling edges
- This is different from the highly symmetric drivers we typically encounter with serial link analysis
- Traditional single-step response methods for impulse response generation may not reproduce circuit simulation results accurately enough
- These slides show how an EDA tool can handle this (without changes to the IBIS specification)
- All cases use **Micron**'s **y11a.ibs** file for 8Gbps DDR5

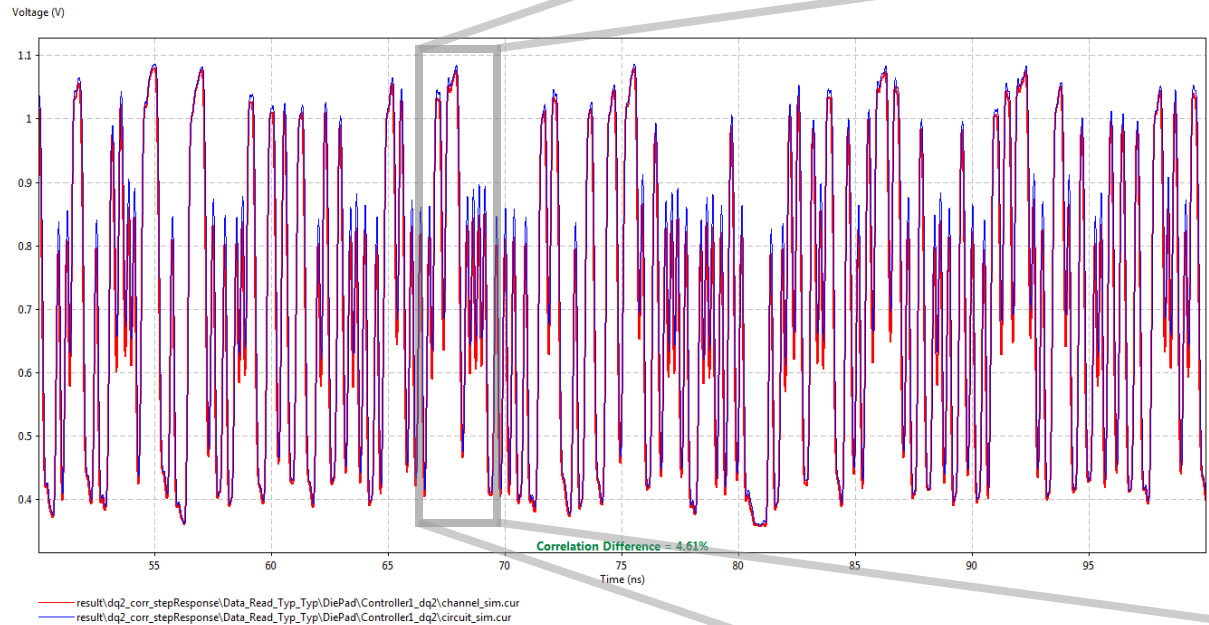
Testbench

- Package block uses an extracted RLCK SPICE model
- PCB block uses W-elements with 0.3 meter lengths

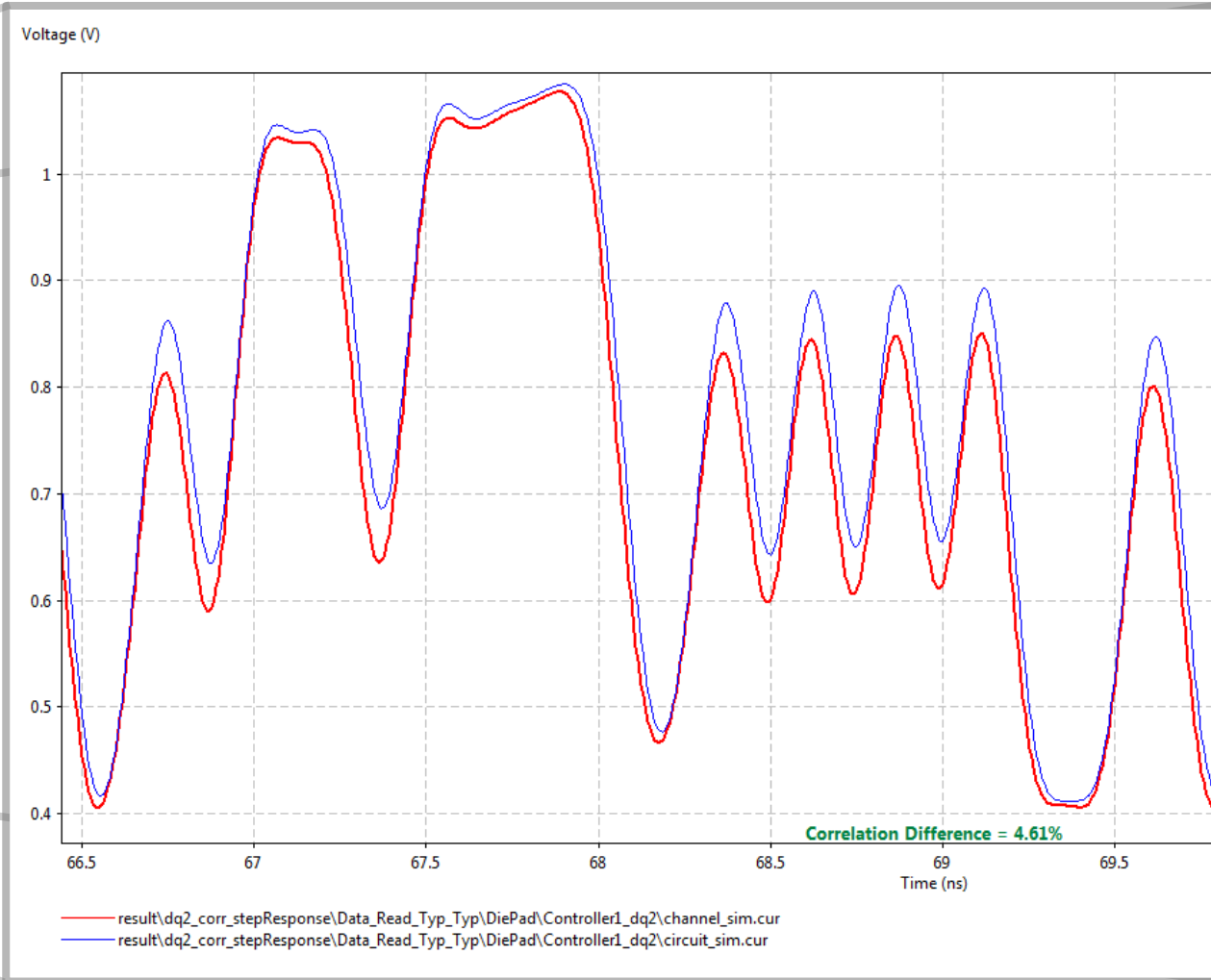


Characterizing with Step Function – One Rising Transition

- Correlation difference 4.61%

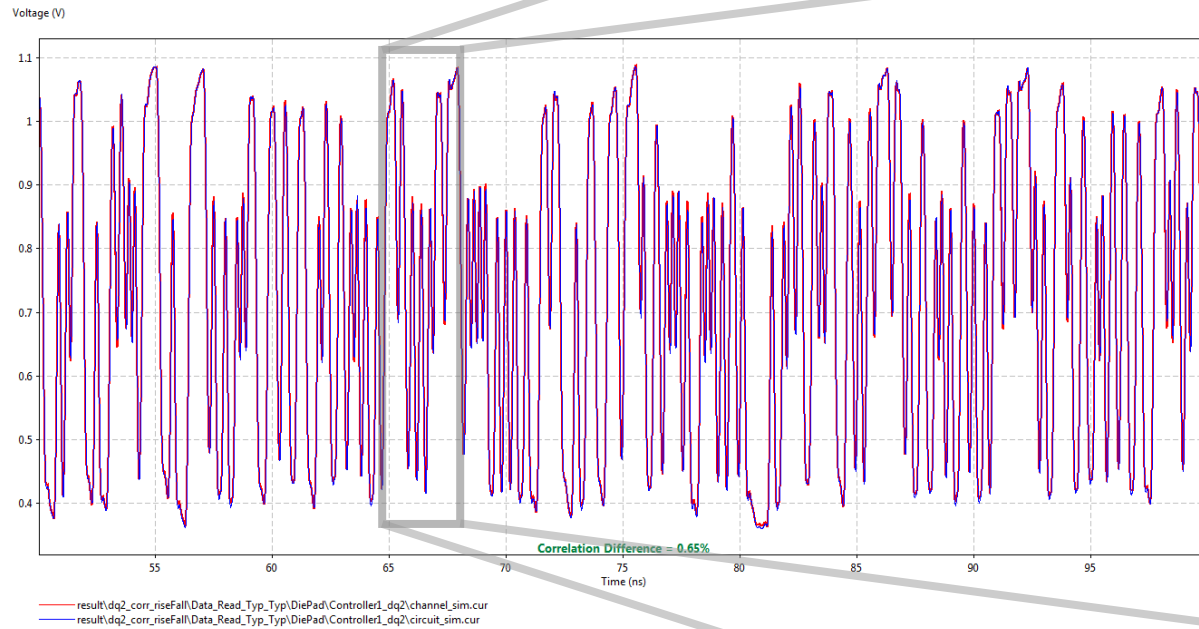


— Circuit Sim
— Channel Sim

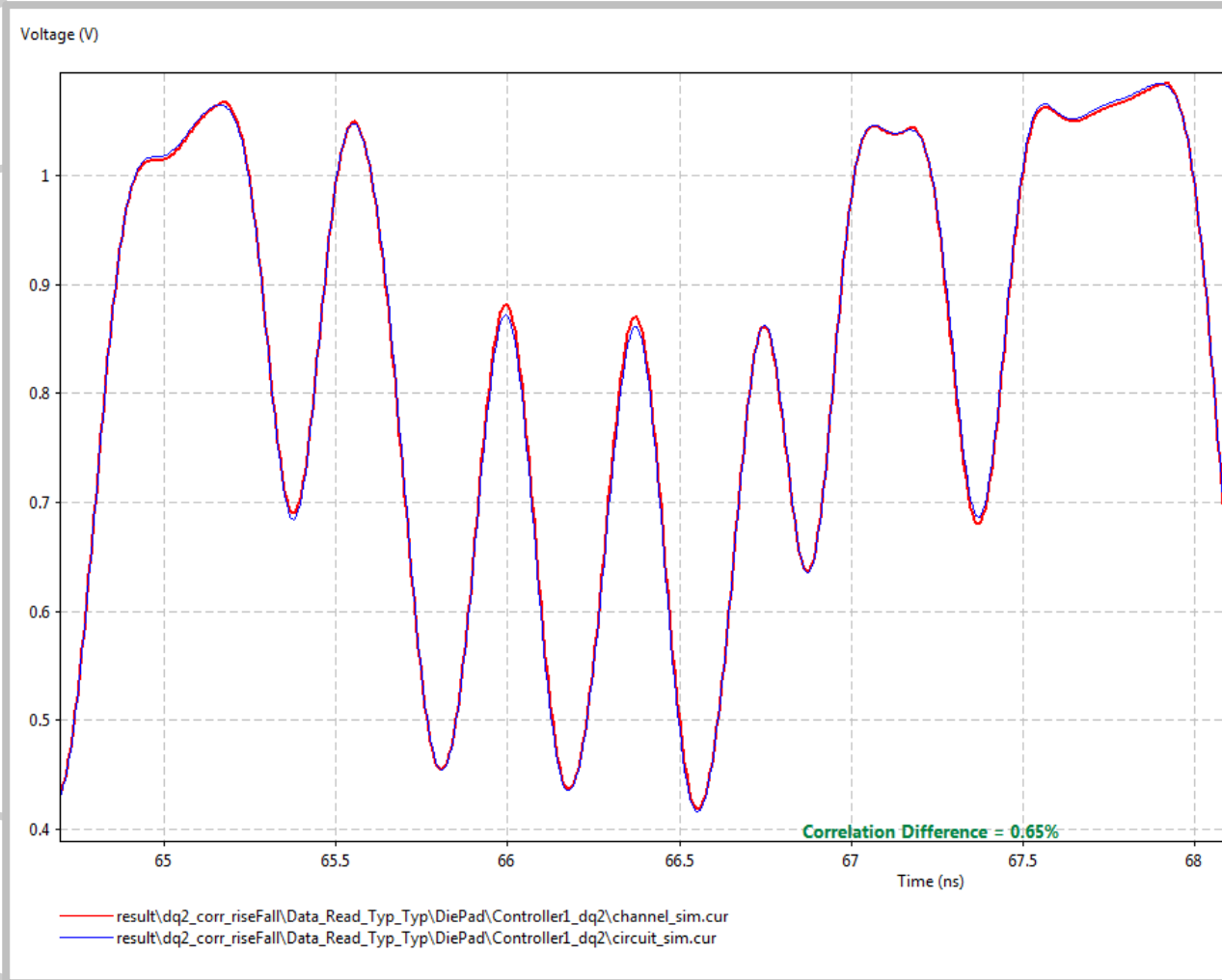


Characterizing with both Rising and Falling Transition

- Correlation difference 0.65%

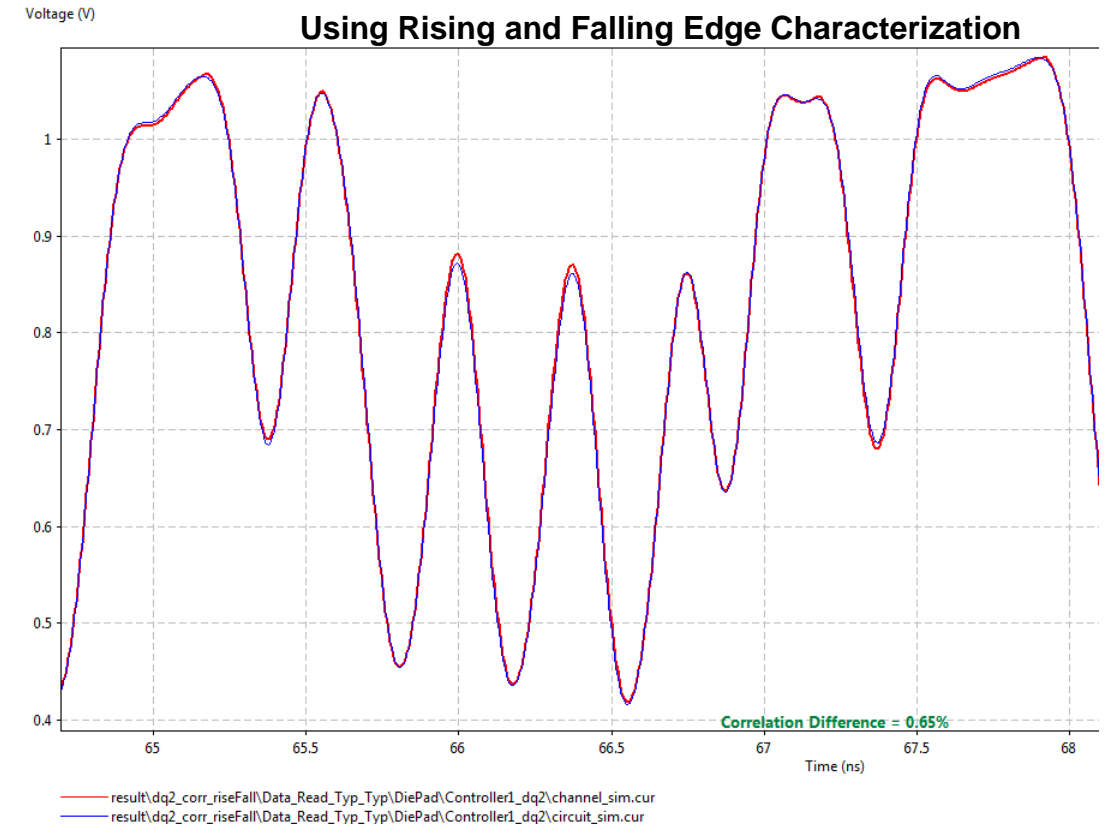
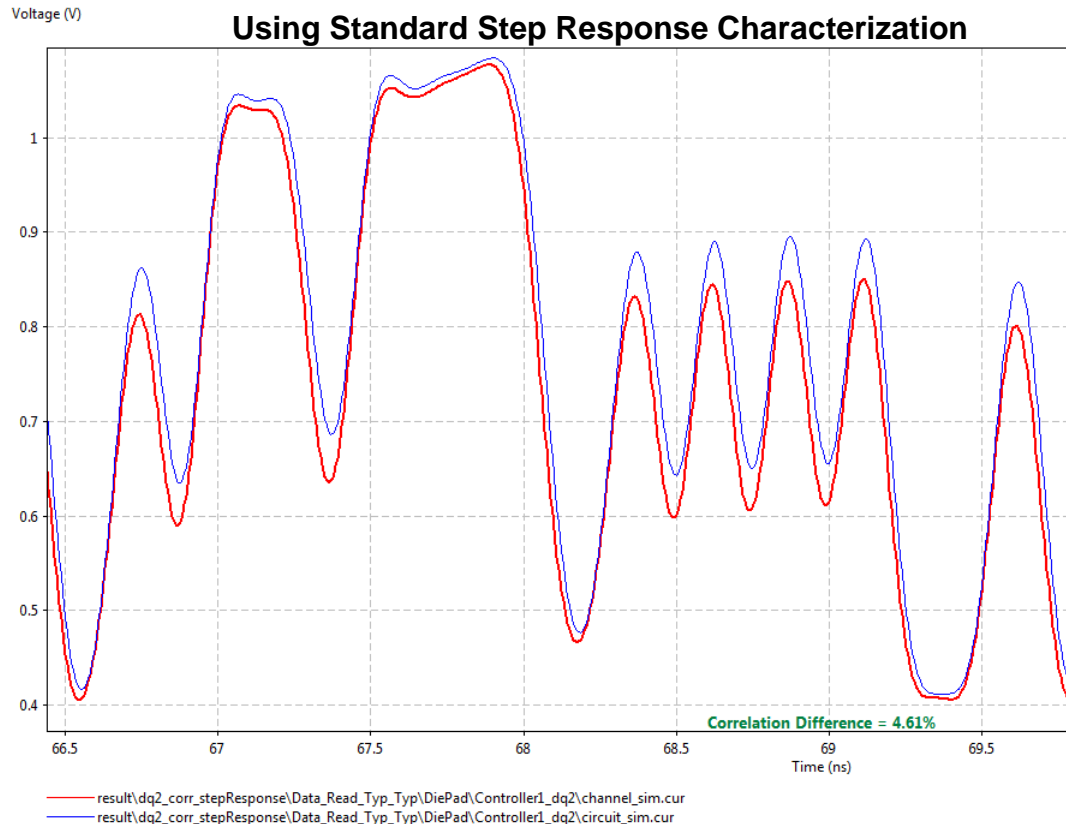


— Circuit Sim
— Channel Sim



Comparison between Two Different Methods

- Correlation error vs. circuit simulation reduced by about 4%



Summary

- The **DQ_34_3600** I/O model has some asymmetry in its rising and falling edges
- Standard SerDes step response characterization did not do a great job in capturing this behavior, as seen in the circuit / channel sim correlation
- Characterization methods using rising and falling edges captured this behavior very well for channel simulation

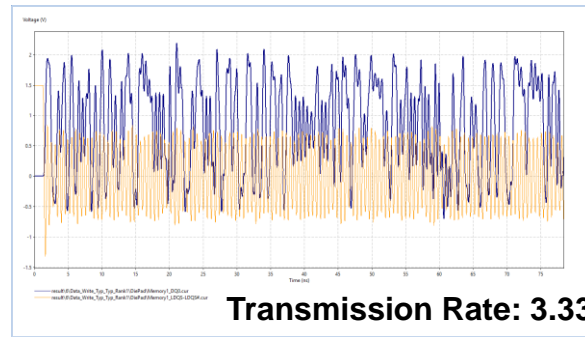
```
|*****|
|
|[Ramp]
R_load = 50
|
|          typ          min          max
|
dV/dt_r 3.7990E-01/6.4024E-11  3.4860E-01/8.7846E-11  4.0938E-01/4.9359E-11
dV/dt_f 4.4605E-01/5.4840E-11  4.2048E-01/7.6564E-11  4.6793E-01/4.2557E-11
|*****|
```



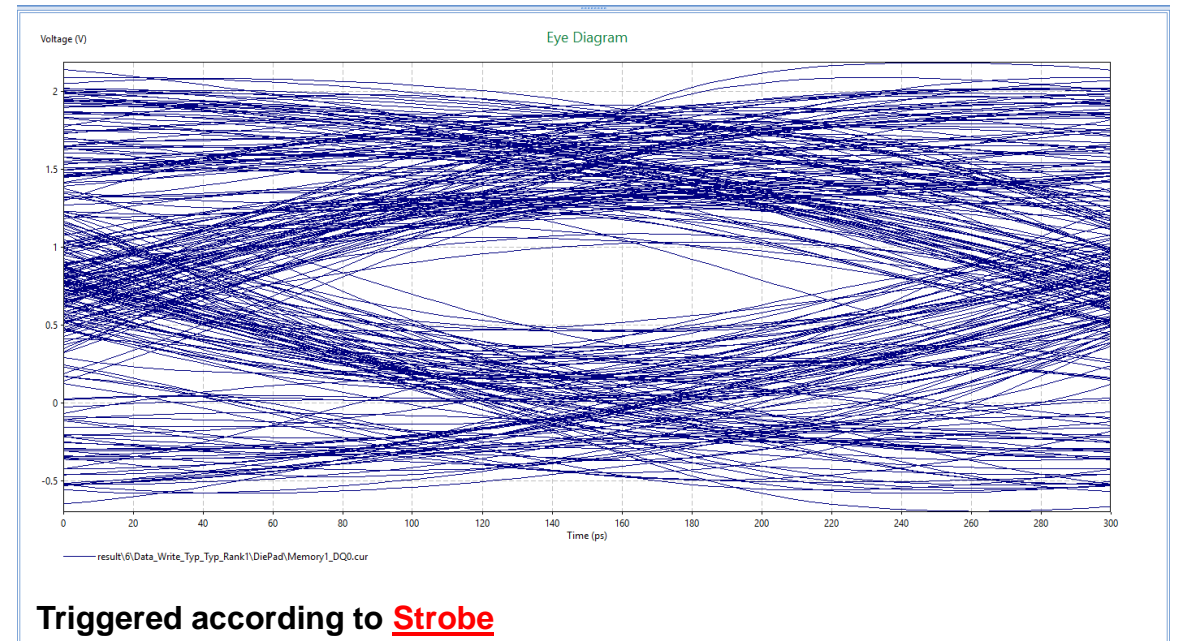
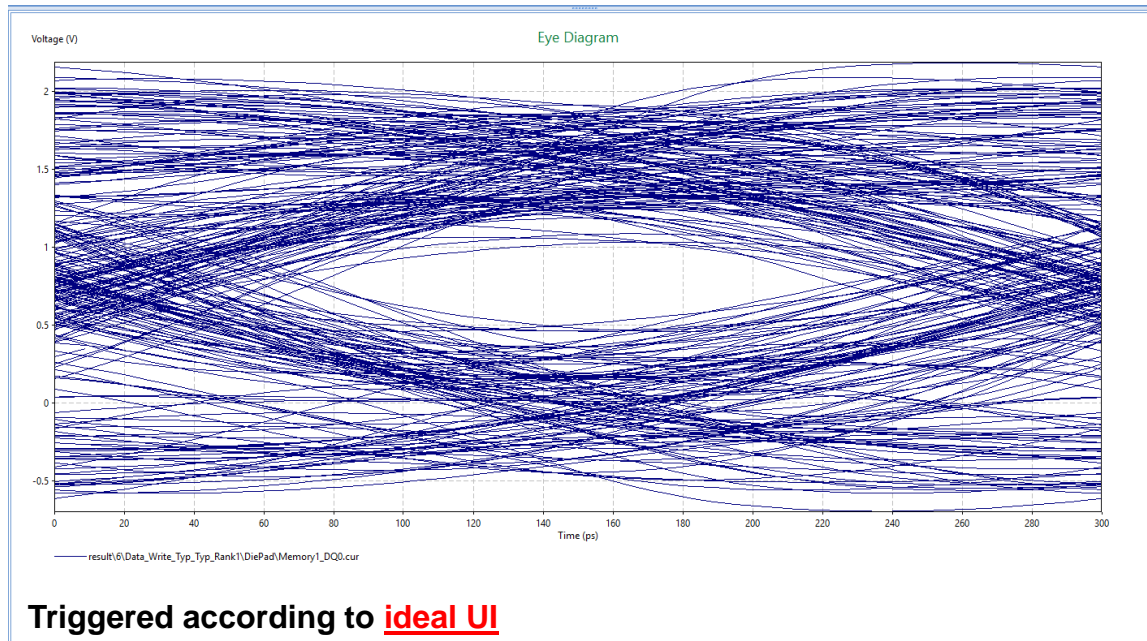
Strobe as Timing Reference

Overview(1)

- Different timing reference – Different selection of “trigger” can result in different eye opening

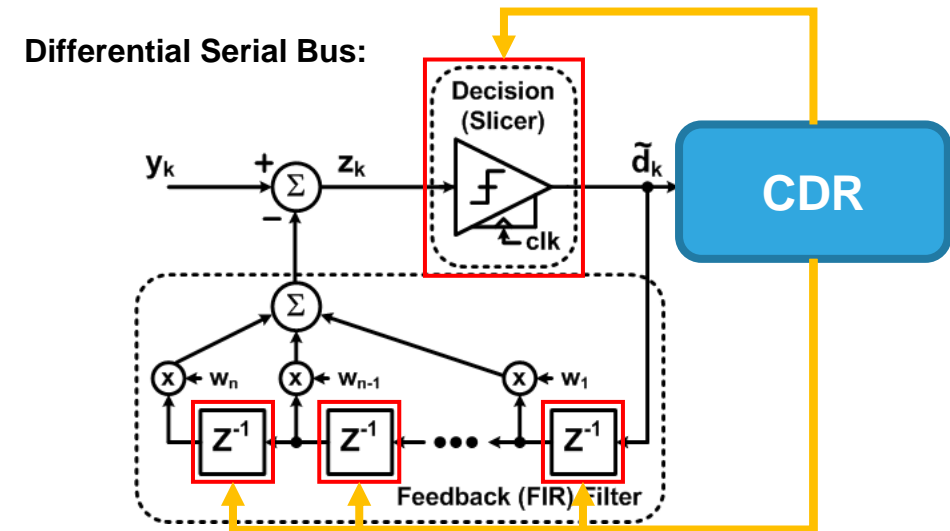
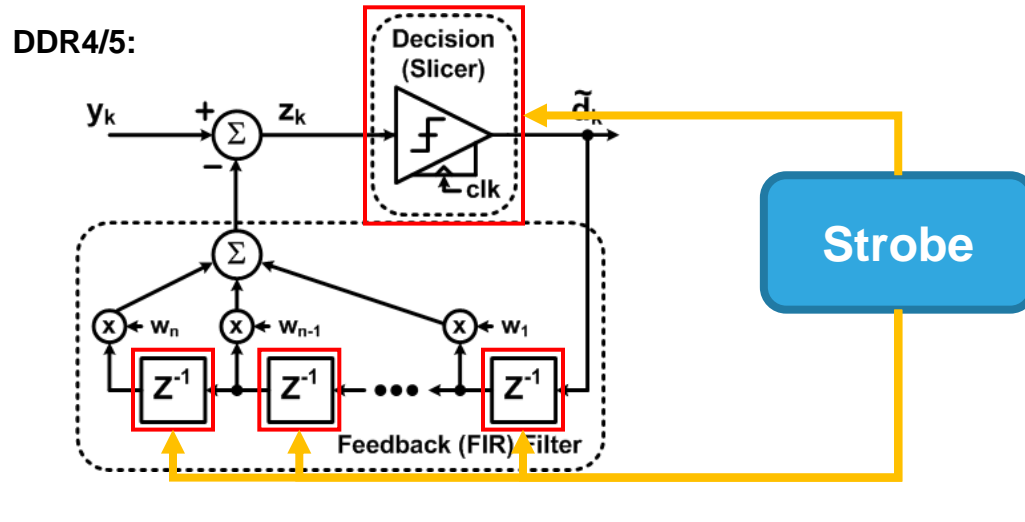


Transmission Rate: 3.333Gbps



Overview(2)

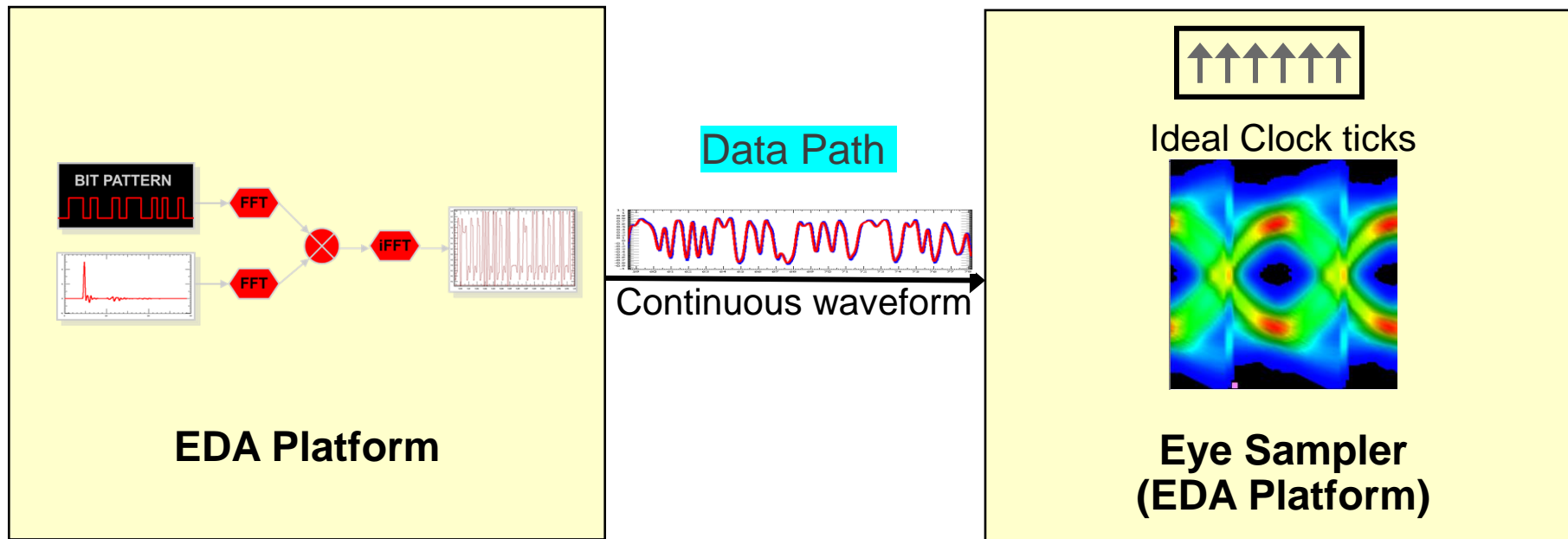
- DFE's clock in memory bus will be supplied by Strobe rather than CDR, which can be seen in most differential serial bus



- As channel simulation and IBIS-AMI modeling methods are adapted from serial link to DDR interface analysis, serial link CDR algorithms are often used for analysis
- What is the impact?

Current CDR-Based Method

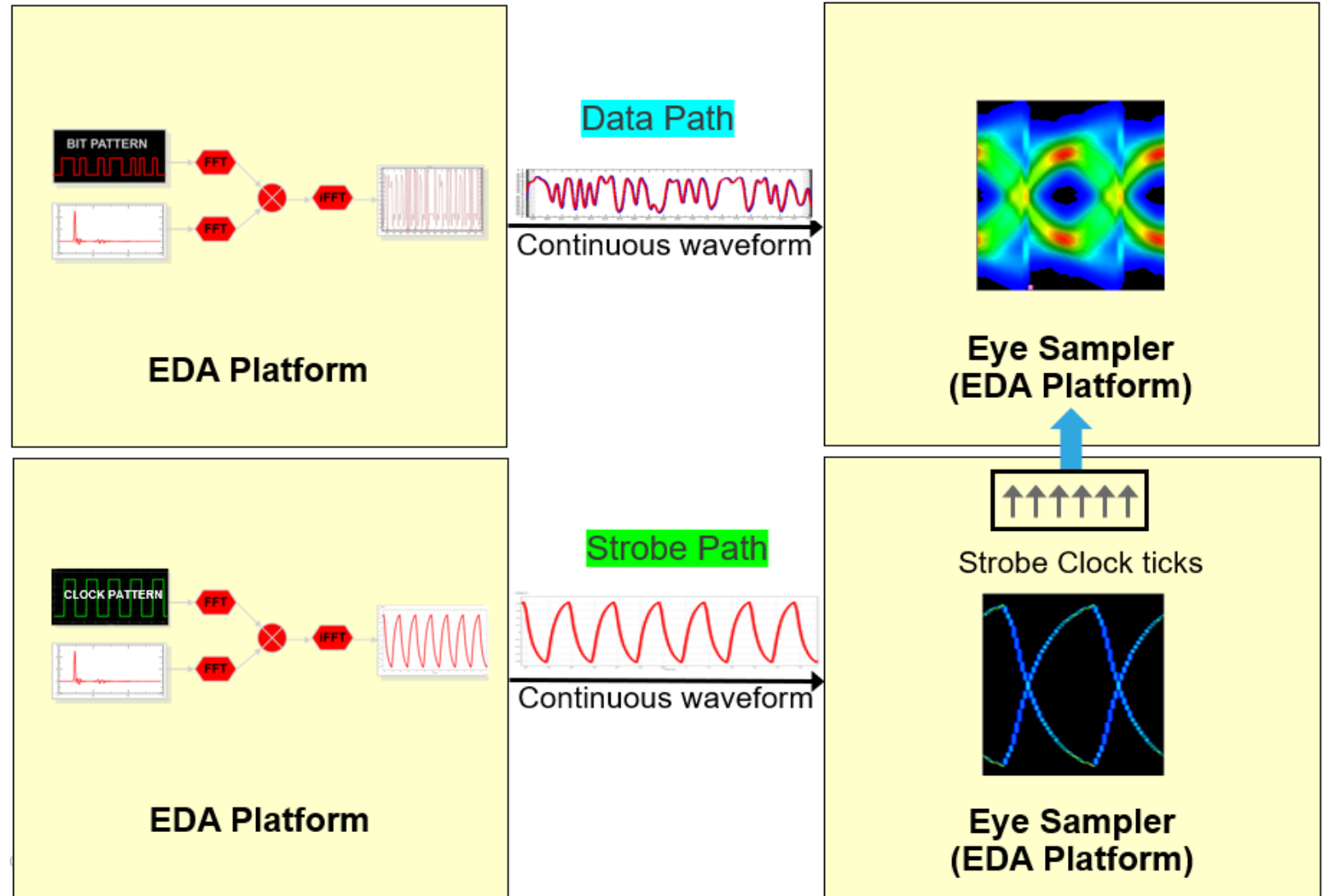
- Centers the eye for each individual signal
 - Ideal clock ticks are generated internally by the eye sampler
 - Clock ticks can also be generated by AMI models and sent to the eye sampler



- Some controllers have some individual bit de-skewing

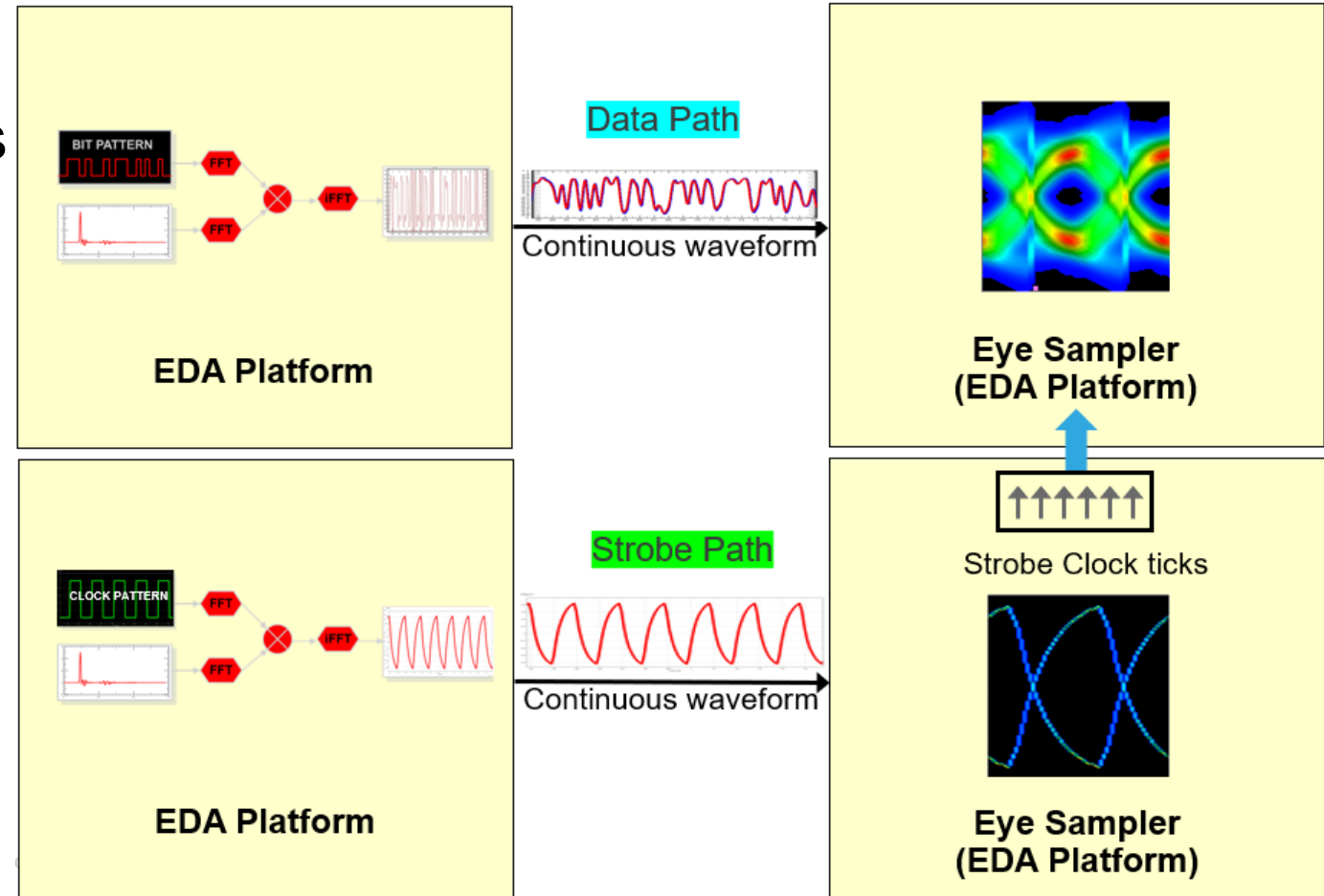
True Strobe Timing (TST)

- Clock ticks are collected from the strobe channel instead of the data channel
 - ❖ With real strobe, this is done for entire byte lane
- Strobe channel is only fed with 0101 data

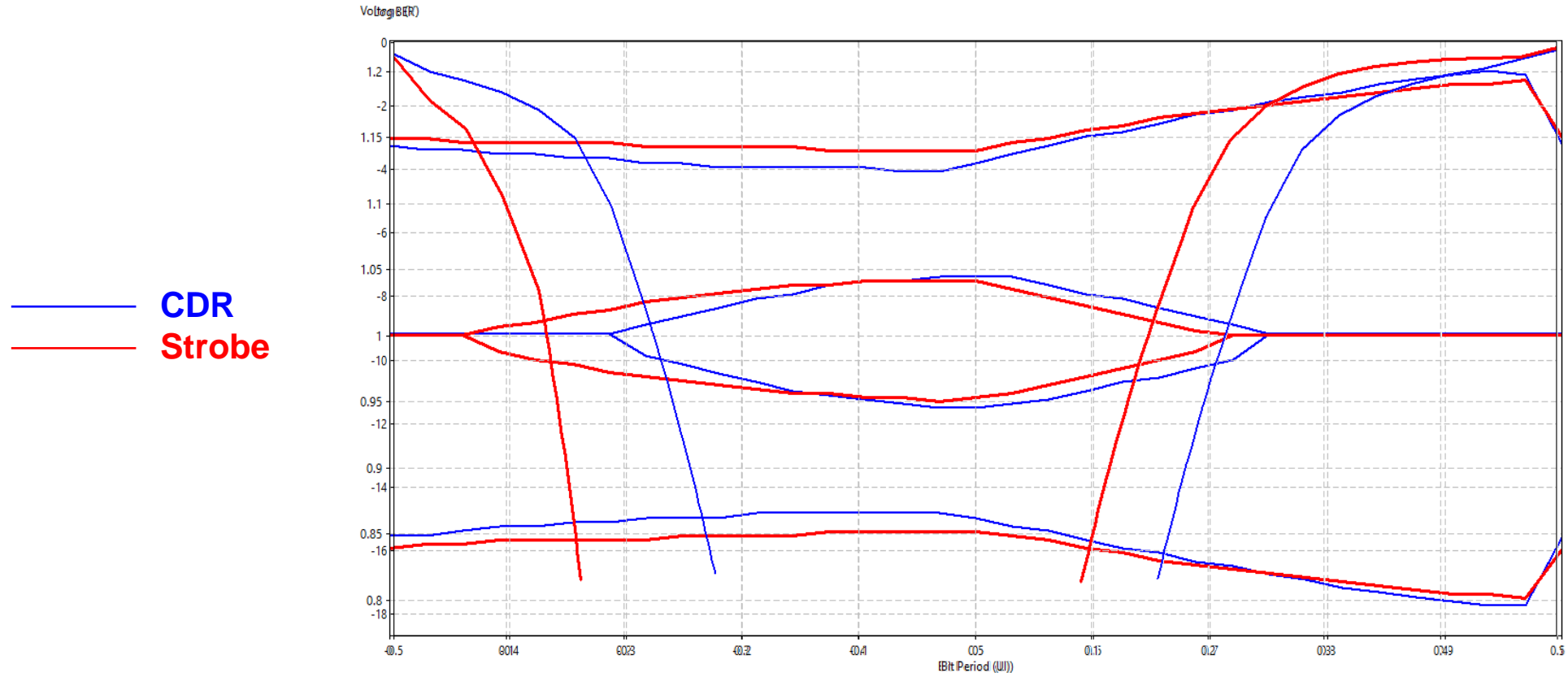


Comparison of Results

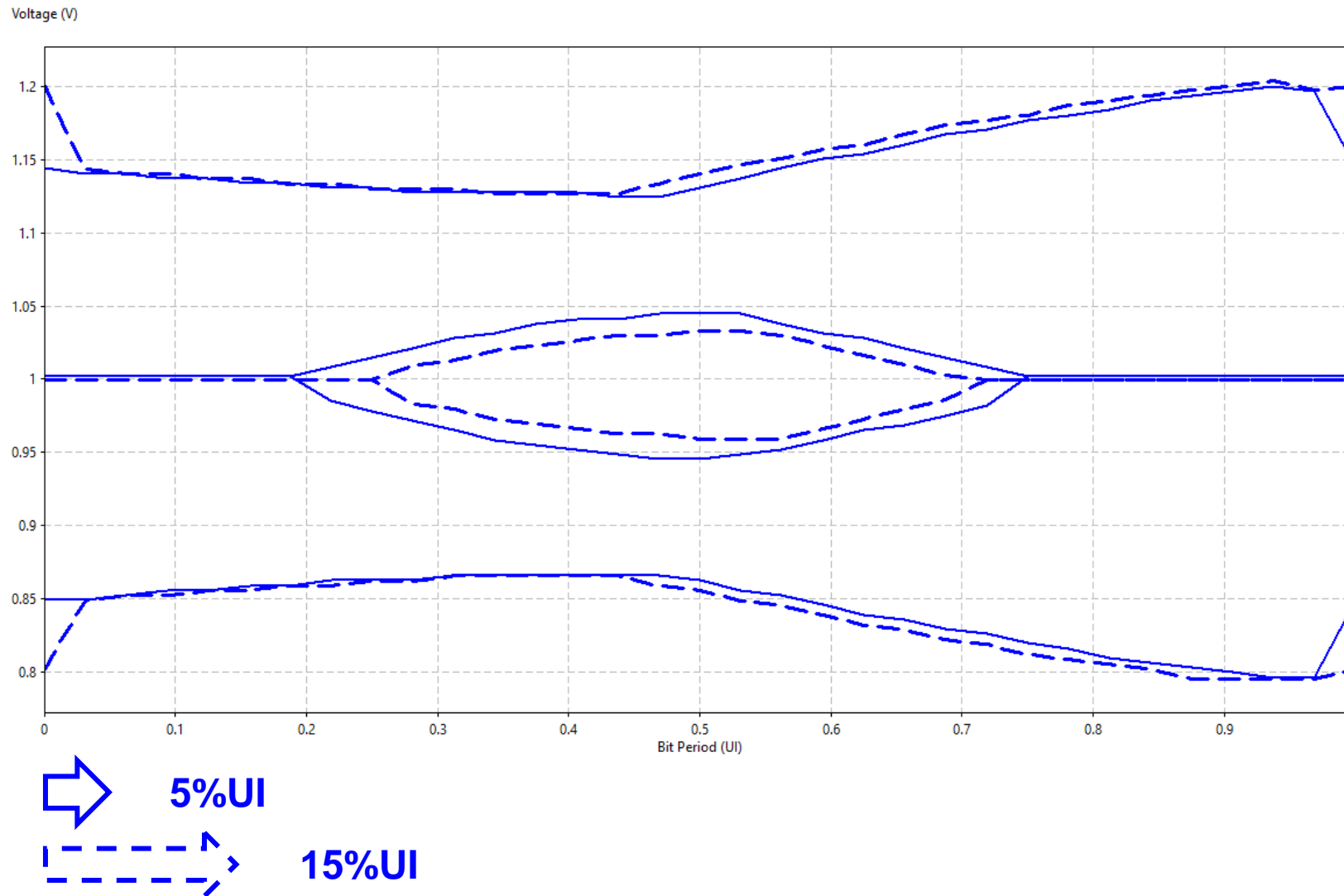
- CDR vs. TST
- CDR vs. TST with jitter impairments
- Test configuration
 - 1 data line is used for simulations
 - 6 Gbps
 - Rx CTLE
 - Rx 4 tap DFE
 - In phase between strobe and data



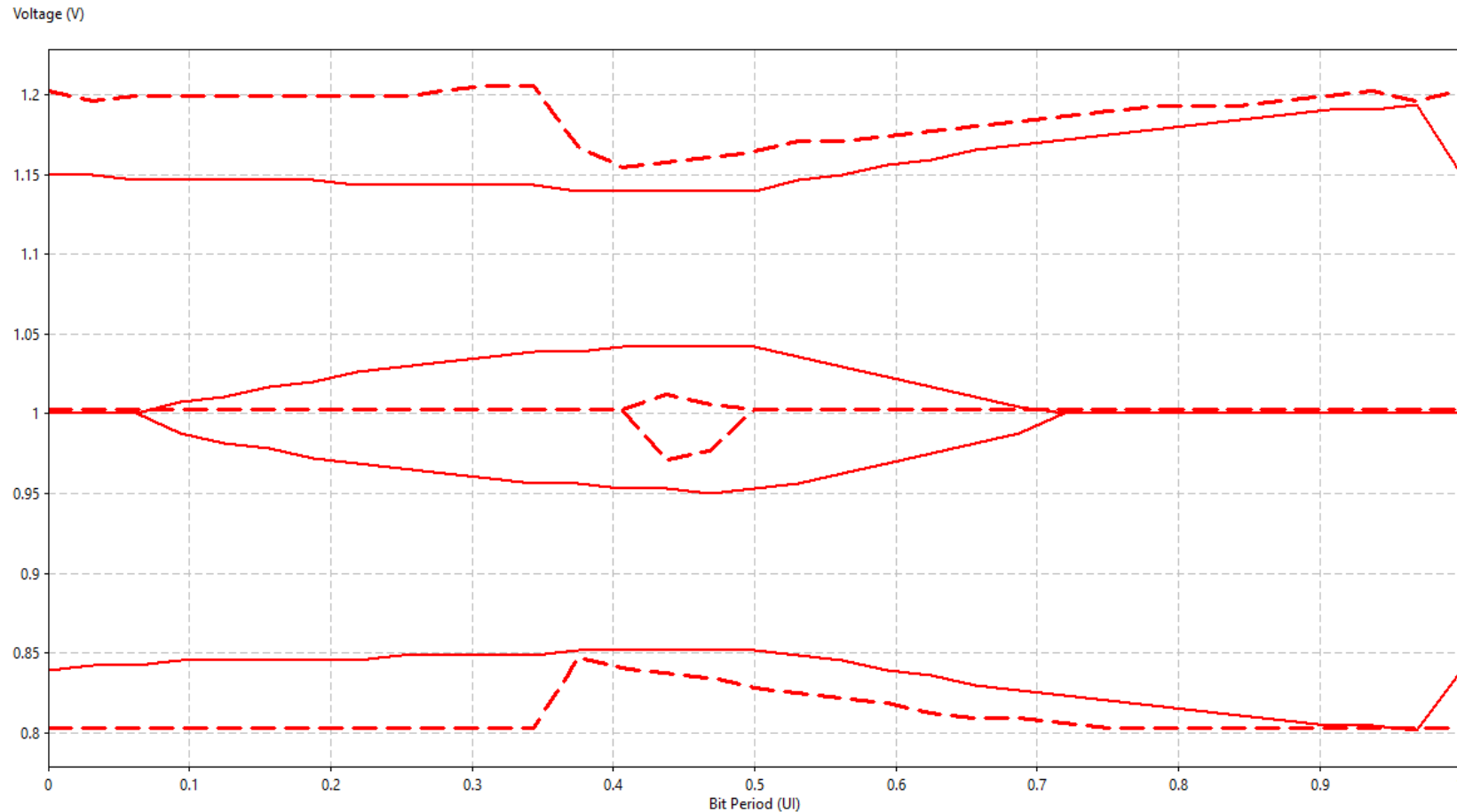
CDR vs. TST


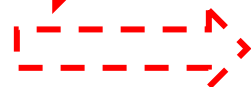


CDR Results with Dj Applied at Tx



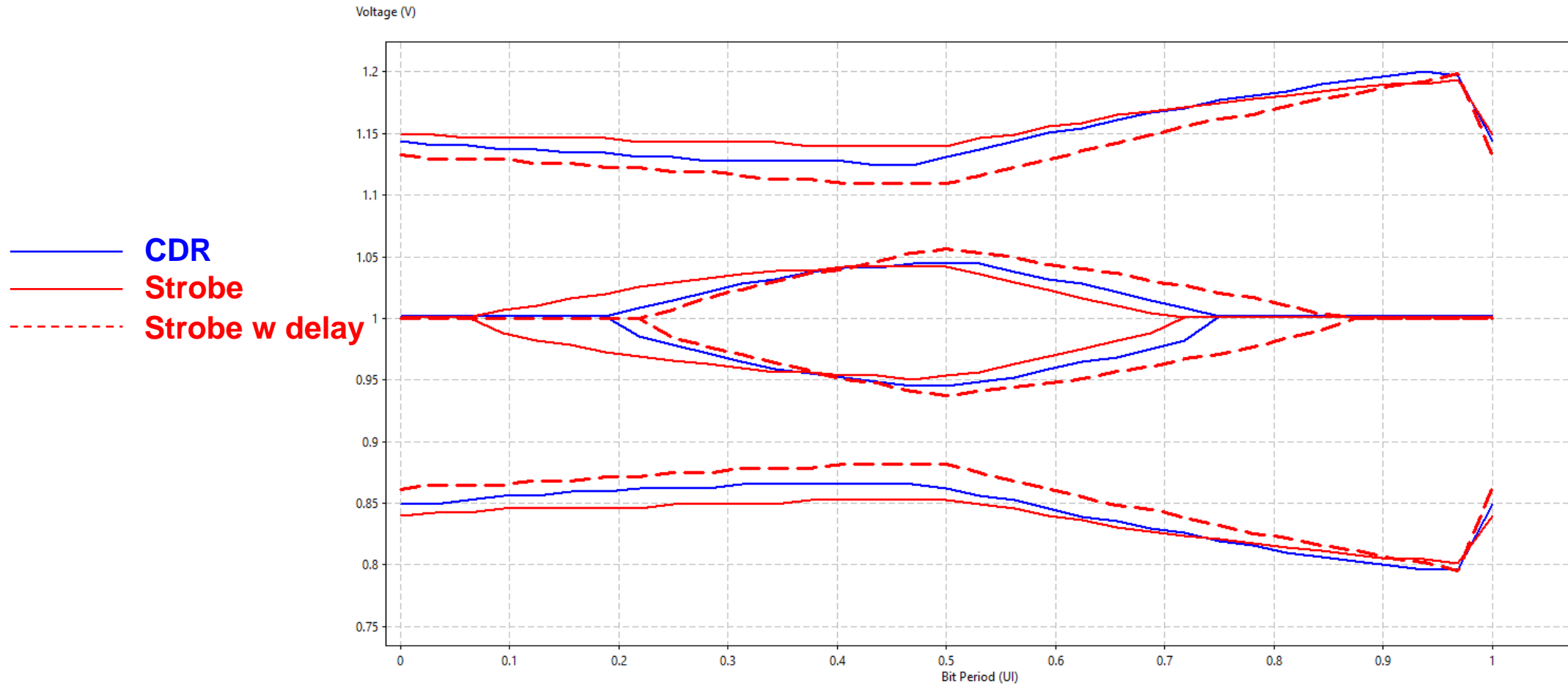
Strobe Results with Dj Applied at Tx



 **5%UI Dj on both strobe and data**
 **15%UI Dj on both strobe and data**

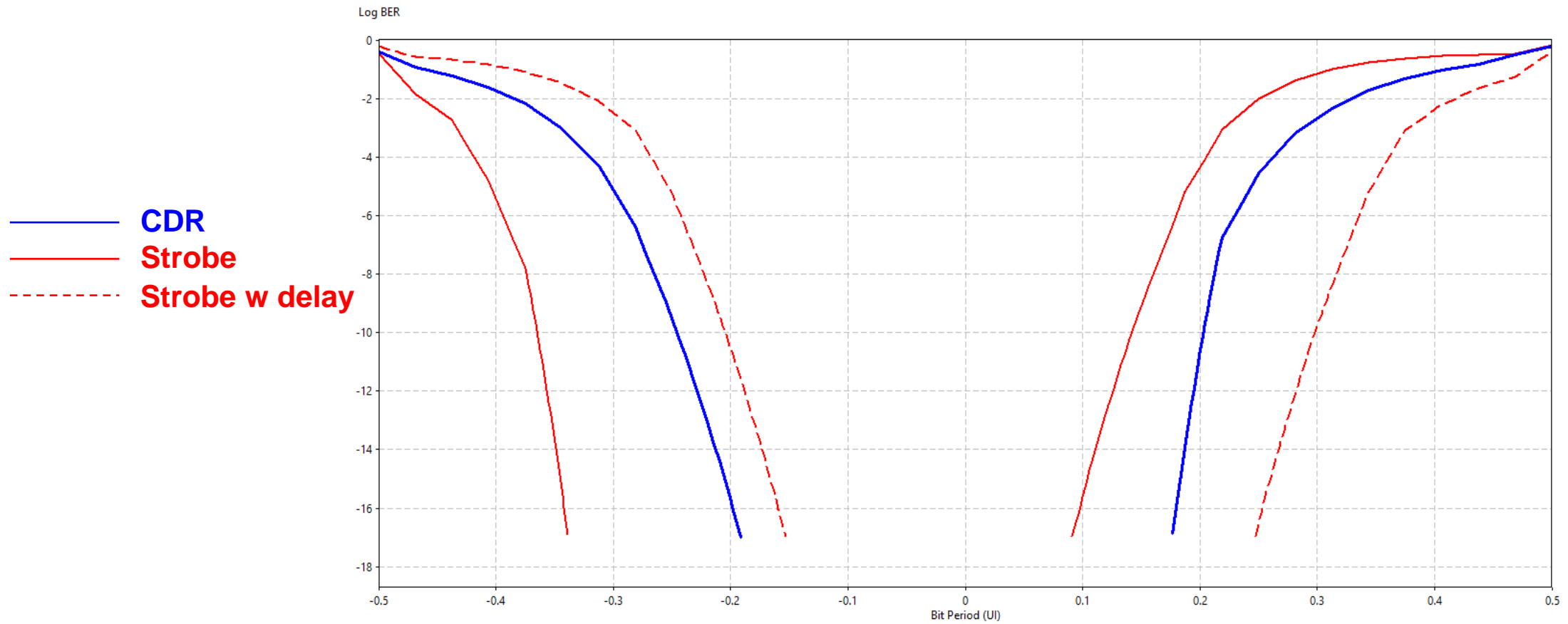
CDR vs. TST

- After delaying by 0.2 UI



CDR vs. TST

- After delaying by 0.2 UI



Summary

- Using default CDR instead of actual strobe to get clock risks will miss important impairments/jitter for parallel bus topology
- Analysis results show false optimism using CDR approach as compared to true strobe timing methodology
- Need to model delay accurately

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